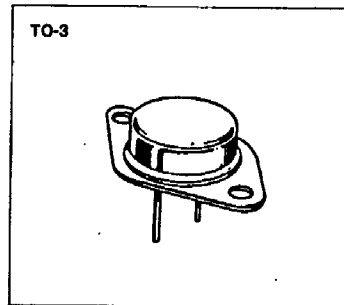


**IRF440/441/442/443**

**N-CHANNEL  
 POWER MOSFETS**

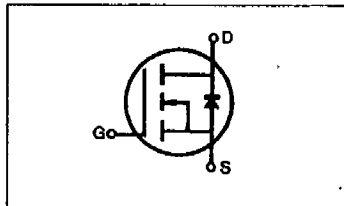
**FEATURES**

- Low  $R_{DS(on)}$  at high voltage
- Improved inductive ruggedness
- Excellent high voltage stability
- Fast switching times
- Rugged polysilicon gate cell structure
- Low input capacitance
- Extended safe operating area
- Improved high temperature reliability
- TO-3 package (High voltage)



**PRODUCT SUMMARY**

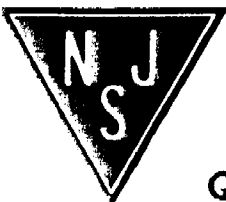
Part Number	$V_{DS}$	$R_{DS(on)}$	$I_D$
IRF440	500V	0.85 $\Omega$	8.0A
IRF441	450V	0.85 $\Omega$	8.0A
IRF442	500V	1.10 $\Omega$	7.0A
IRF443	450V	1.10 $\Omega$	7.0A



**MAXIMUM RATINGS**

Characteristic	Symbol	IRF440	IRF441	IRF442	IRF443	Unit
Drain-Source Voltage (1)	$V_{DSS}$	500	450	500	450	Vdc
Drain-Gate Voltage ( $R_{GS}=1.0M\Omega$ ) (1)	$V_{DGR}$	500	450	500	450	Vdc
Gate-Source Voltage	$V_{GS}$	$\pm 20$				Vdc
Continuous Drain Current $T_C=25^\circ C$	$I_D$	8.0	8.0	7.0	7.0	Adc
Continuous Drain Current $T_C=100^\circ C$	$I_D$	5.0	5.0	4.0	4.0	Adc
Drain Current—Pulsed (3)	$I_{DM}$	32	32	28	28	Adc
Gate Current—Pulsed	$I_{GM}$	$\pm 1.5$				Adc
Total Power Dissipation @ $T_C=25^\circ C$ Derate above $25^\circ C$	$P_D$	125 1.0				Watts W/ $^\circ C$
Operating and Storage Junction Temperature Range	$T_J, T_{stg}$	-55 to 150				$^\circ C$
Maximum Lead Temp. for Soldering Purposes, 1/8" from case for 5 seconds	$T_L$	300				$^\circ C$

Notes: (1)  $T_J=25^\circ C$  to  $150^\circ C$   
 (2) Pulse test: Pulse width  $\leq 300\mu s$ , Duty Cycle  $\leq 2\%$   
 (3) Repetitive rating: Pulse width limited by max. junction temperature



NJ Semi-Conductors reserves the right to change test conditions, parameter limits and package dimensions without notice. Information furnished by NJ Semi-Conductors is believed to be both accurate and reliable at the time of going to press. However, NJ Semi-Conductors assumes no responsibility for any errors or omissions discovered in its use. NJ Semi-Conductors encourages customers to verify that datasheets are current before placing orders.

**Quality Semi-Conductors**

# IRF440/441/442/443

# N-CHANNEL POWER MOSFETS

## ELECTRICAL CHARACTERISTICS (T<sub>C</sub>=25°C unless otherwise specified)

Characteristic	Symbol	Type	Min	Typ	Max	Units	Test Conditions
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	IRF440	500	—	—	V	V <sub>GS</sub> =0V I <sub>D</sub> =250μA
		IRF442					
		IRF441	450	—	—	V	
		IRF443					
Gate Threshold Voltage	V <sub>GS(th)</sub>	ALL	2.0	—	4.0	V	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA
Gate-Source Leakage Forward	I <sub>GSS</sub>	ALL	—	—	100	nA	V <sub>GS</sub> =20V
Gate-Source Leakage Reverse	I <sub>GSS</sub>	ALL	—	—	-100	nA	V <sub>GS</sub> =-20V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	ALL	—	—	250	μA	V <sub>DS</sub> =Max. Rating, V <sub>GS</sub> =0V
			—	—	1000	μA	V <sub>DS</sub> =Max. Rating×0.8, V <sub>GS</sub> =0V, T <sub>C</sub> =125°C
On-State Drain-Source Current (2)	I <sub>D(on)</sub>	IRF440	8.0	—	—	A	V <sub>DS</sub> >I <sub>D(on)</sub> ×R <sub>DS(on) max.</sub> , V <sub>GS</sub> =10V
		IRF441					
		IRF442	7.0	—	—	A	
		IRF443					
Static Drain-Source On-State Resistance (2)	R <sub>DS(on)</sub>	IRF440	—	0.6	0.85	Ω	V <sub>GS</sub> =10V, I <sub>D</sub> =4.0A
		IRF441					
		IRF442	—	1.0	1.1	Ω	
		IRF443					
Forward Transconductance (2)	g <sub>fs</sub>	ALL	4.0	6.5	—	Ω	V <sub>DS</sub> >I <sub>D(on)</sub> ×R <sub>DS(on) max.</sub> , I <sub>D</sub> =4.0A
Input Capacitance	C <sub>iss</sub>	ALL	—	1200	1600	pF	V <sub>GS</sub> =0V, V <sub>DS</sub> =25V, f=1.0MHz
Output Capacitance	C <sub>oss</sub>	ALL	—	230	350	pF	
Reverse Transfer Capacitance	C <sub>rss</sub>	ALL	—	65	150	pF	
Turn-On Delay Time	t <sub>d(on)</sub>	ALL	—	—	35	ns	V <sub>DD</sub> =0.5BV <sub>DSS</sub> , I <sub>D</sub> =4.0A, Z <sub>O</sub> =4.7 Ω (MOSFET switching times are essentially independent of operating temperature.)
Rise Time	t <sub>r</sub>	ALL	—	—	15	ns	
Turn-Off Delay Time	t <sub>d(off)</sub>	ALL	—	—	90	ns	
Fall Time	t <sub>f</sub>	ALL	—	—	30	ns	
Total Gate Charge (Gate-Source Plus Gate-Drain)	Q <sub>g</sub>	ALL	—	34	60	nC	
Gate-Source Charge	Q <sub>gs</sub>	ALL	—	6.0	—	nC	V <sub>GS</sub> =10V, I <sub>D</sub> =10A, V <sub>DS</sub> =0.8 Max. Rating (Gate charge is essentially independent of operating temperature.)
Gate-Drain ("Miller") Charge	Q <sub>gd</sub>	ALL	—	28	—	nC	

## THERMAL RESISTANCE

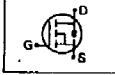
Junction to Case	R <sub>thJC</sub>	ALL	—	—	1.0	K/W	
Case-to-Sink	R <sub>thCS</sub>	ALL	—	0.1	—	K/W	Mounting surface flat, smooth, and greased
Junction-to-Ambient	R <sub>thJA</sub>	ALL	—	—	30	K/W	Free Air Operation

- Notes: (1) T<sub>C</sub>=25°C to 150°C  
 (2) Pulse test: Pulse width<300μs, Duty Cycle<2%  
 (3) Repetitive rating: Pulse width limited by max. junction temperature

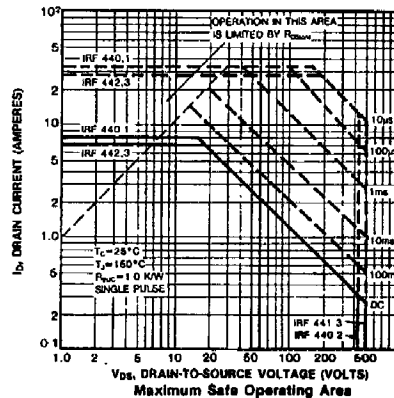
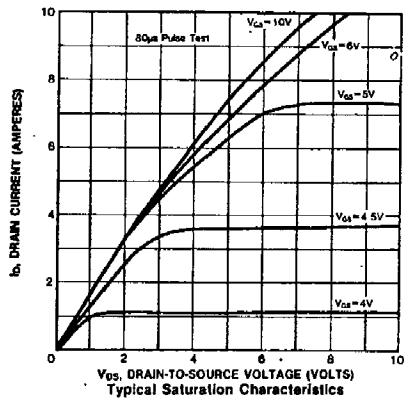
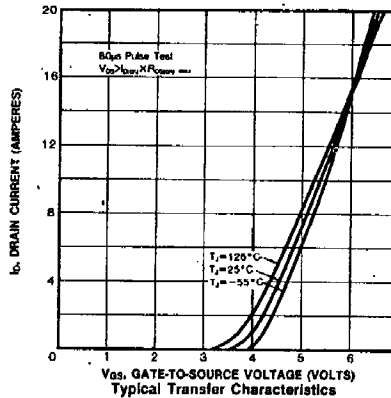
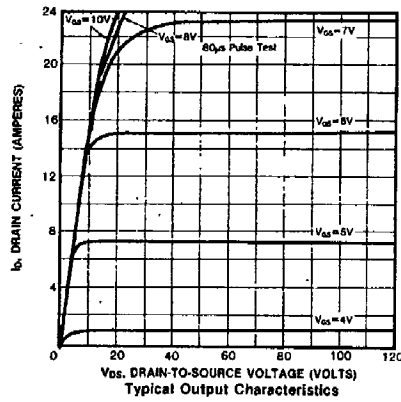
# IRF440/441/442/443

# N-CHANNEL POWER MOSFETS

## SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS

Characteristic	Symbol	Type	Min	Typ	Max	Units	Test Conditions
Continuous Source Current (Body Diode)	$I_S$	IRF440 IRF441	—	—	8.0	A	Modified MOSFET symbol showing the integral reverse P-N junction rectifier 
		IRF442 IRF443	—	—	7.0	A	
Pulse Source Current (Body Diode) (3)	$I_{SM}$	IRF440 IRF441	—	—	32	A	
		IRF442 IRF443	—	—	28	A	
Diode Forward Voltage (2)	$V_{SD}$	IRF440 IRF441	—	—	2.0	V	$T_C=25^\circ\text{C}$ , $I_S=8.0\text{A}$ , $V_{GS}=0\text{V}$
		IRF442 IRF443	—	—	1.9	V	$T_C=25^\circ\text{C}$ , $I_S=7.0\text{A}$ , $V_{GS}=0\text{V}$
Reverse Recovery Time	$t_{rr}$	ALL	—	1100	—	ns	$T_J=150^\circ\text{C}$ , $I_F=8.0\text{A}$ , $dI_F/dt=100\text{A}/\mu\text{s}$

Notes: (1)  $T_J=25^\circ\text{C}$  to  $150^\circ\text{C}$  (2) Pulse test: Pulse width  $\leq 300\mu\text{s}$ , Duty Cycle  $\leq 2\%$   
 (3) Repetitive rating: Pulse width limited by max. junction temperature



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